

IEC QUALITY ASSESSMENT SYSTEM (IECQ) covering Electronic Components, Assemblies, Related Materials and Processes

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Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 16.0003-02

CB Certificate No.: 20002490 ITL

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Appendix-1 (20002490 ITL) Schedule of Scope to Certificate of Approval

Description test	Standard
Scanning Electron Microscope (SEM)	T-SEM-3
Energy Dispersive Spectrometry of X-ray (EDS)	T-SEM-3, T-TEM-3
Focused Ion Beam microscope (FIB)	T-FIB-3
X-Ray	T-EFA-3
Emission Microscopy (EMMI)	T-EFA-3
EMMI-InGaAs	T-EFA-3
Optical Beam Induced Resistance Change (OBIRCH)	T-EFA-3
Scanning Acoustic Tomography (SAT)	T-EFA-3
Optical Microscope (OM)	T-OMI-3
3D Optical Microscope (3D OM)	T-LAB-3
IC Layout Imaging	T-OMI-3
Circuitry analysis	T-OMI-3
THEMOS	T-EFA-3

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Date: 7/15/2022

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